

<b>Notice of References Cited</b>	Application/Control No. 10/020,872	Applicant(s)/Patent Under Reexamination CHEON LEE, BYUNG	
	Examiner Andrew C. Lee	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,636,510	10-2003	Lee et al.	370/390
*	B	US-6,597,698	07-2003	Lundback et al.	370/398
*	C	US-5,689,506	11-1997	Chiussi et al.	370/388
*	D	US-6,747,974	06-2004	Hayashi, Kentaro	370/395.1
*	E	US-5,963,552	10-1999	Joo et al.	370/395.32
*	F	US-6,522,647	02-2003	Czajkowski et al.	370/356
*	G	US-6,597,696	07-2003	Toyama et al.	370/395.31
*	H	US-7,116,658	10-2006	Almalki, Safa	370/356
*	I	US-6,594,267	07-2003	Dempo, Hiroshi	370/395.64
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.